# Symposium on Counterfeit Electronic Parts West 2010

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## Symposium on Counterfeit Electronic Parts West

June 8 – 11, 2010 Phoenix, Arizona

#### **TABLE OF CONTENTS**

## **Keynote**

Counterfeiting in the Context of International Trade \$\$% Stan McCoy, Office of the U.S. Trade Representative

### Keynote

Counterfeits and the U.S. Industrial Base \$&& Mark Crawford, US Department of Commerce

#### **Session 1**

Intellectual Property Enforcement - Competing for Limited Resources \$) + Tim Trainer, Global Intellectual Property Strategy Center, P.C.

Criminal Prosecutions of Counterfeit Technology: Common Concerns, Solutions and Case Studies \$+%

Richard Nelson and Louis Feuchtbaum, Sideman & Bancroft LLP

Combating Counterfeit Electronics \$-+

John M. Butler, Naval Sea Systems Command, SEA04P

### **Panel**

#### **US Law Enforcement Panel Discussion**

Panelists:

William "Jay" Strauch, *Defense Criminal Investigative Service* F€Î Karin Jarman, *Intellectual Property Rights Unit, FBI Ā*FFH Erin Michaels, *Naval Criminal Investigative Service* FFÍ Corbin Wickman and Edward Tarver, *ICE Investigations Ā*FGÍ

#### Session 2

## Counterfeit EEE Parts Risk Mitigation-G19 Activities % \*

Dan DiMase, Honeywell

## MDA Site Visits, AS6081 Distributor Assessments % (

Fred Schipp, MDA-QS

## How to Think About Counterfeits – Evaluating Anti-Counterfeit Partners and Strategies with Business Fundamentals % -

Philip Comer, DMEA

## X-Ray Inspection Systems for Counterfeit Detection &\$%

Bill Cardoso, Ph.D., Adrian Nishimoto, and Justin White, *Creative Electron, Inc;* David Loaney, *Premier Semiconductor Services* 

## **Keynote**

## Counterfeits in the U.S. Supply Chain &&%

Belva Martin, U.S. Government Accountability Office

### Session 3

## Counterfeit Detection using Heated Solvents & +

Tom Sharpe, SMT Corporation

## Material Characterization Techniques for Part Authentication & \$

Bhanu Sood, CALCE/University of Maryland

#### Session 4

## Spectroscopic Fingerprinting of Electronic Parts ' ' &

Sharon Flank, InfraTrac

## Engaging the Consumer with Technology to Facilitate Proactive Prevention ' (-

Huda Midani, Schreiner ProSecure

## Strategies for Fighting Counterfeit Electronics - Track and Trace Begins at WIP ' +% James Williams, Ph.D., *Polyonics, Inc.*

## Verifying Trust for Defense Use Commercial Electronics ( &\$

Sydney Pope, *Department of Defense;* Brian S. Cohen, Vashisht Sharma, R. R. Wagner and Loren W. Linholm, *Institude for Defense Analyses;* S. Gillespie, *Potomac Institute for Policy Studies* 

#### **Panel**

## **Supply Chain Panel Discussion**

Panelists:

Bob Bodemuller, *Ball Aerospace & Technologies* Á I Î Robin B. Gray, Jr., *National Electronic Distributors Association* I Í Ì Lisa Maestas, *Texas Instruments Incorporated* Á Î Í Fred Schipp, *MDA-QS* Á JG Tom Sharpe, *SMT Corporation* Á €G

### Session 5

# Counterfeit Part Detection in Assembled Products – Case Studies from the NASA Johnson Space Center ') +)

Dan Hartgerink, NASA, W. David Beverly Receiving Inspection Test Facility

Counterfeit Prevention & Detection Strategies - Cost Versus Risk Assessment ') - + Craig Hillman, Greg Caswell, Nathan Blattau and Randy Kong, *DfR Solutions* 

Counterfeit Trends – Increasing Difficulties in Detection \*\* &\* Mark Marshall, Integra Technologies

Research Directions to Identify and Address Future Challenges \*(-Diganta Das, Ph.D., CALCE/University of Maryland